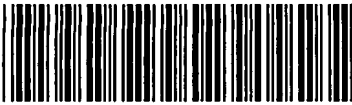


Search Notes

Application/Control No.

10/784,820

Examiner

Tan V. Mai

Applicant(s)/Patent under
Reexamination

YIP ET AL.

Art Unit

2193

SEARCHED

Class	Subclass	Date	Examiner
updated	search	11/19/2007	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search (see search history printout(s))	11/19/2007	MAI